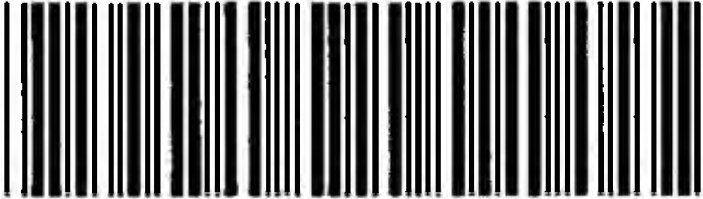


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,462	CHEN, YU-CHEN	
	Examiner	Art Unit	
	David Mis	2817	

SEARCHED			
Class	Subclass	Date	Examiner
331	45, 57, 74, 75	3/17/2005	DM
327	116,		
	119-123,		
	291, 193,		
	294, 298		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
as	above	3/17/2005	DM

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR